N-channel LFPAK 80 V 12.9 m Ω standard level MOSFET

Rev. 01 — 25 June 2009

Product data sheet

1. Product profile

Table 1.

1.1 General description

Standard level N-channel MOSFET in LFPAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power converters

1.3 Applications

Quick reference

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

1.4 Quick reference data

- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package
- Motor control
- Server power supplies

Table 1.	QUICK TETETETICE					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	-	80	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	-	-	60	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	106	W
Tj	junction temperature		-55	-	175	°C
Avalanc	he ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 55 A; V_{sup} \leq 80 V; R_{GS} = 50 Ω ; unclamped	-	-	70	mJ
Dynamic	characteristics					
Q_{GD}	gate-drain charge	V_{GS} = 10 V; I_D = 25 A; V_{DS} = 40 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	8	-	nC
Q _{G(tot)}	total gate charge	V_{GS} = 10 V; I_D = 25 A; V_{DS} = 40 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	37	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state	V_{GS} = 10 V; I _D = 15 A; T _j = 100 °C; see <u>Figure 12</u>	-	-	19.8	mΩ
	resistance	V_{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 13</u>	-	9.7	12.9	mΩ



2. Pinning information

Table 2.	Pinning	information				
Pin	Symbol	Description	Simplified outline	Graphic symbol		
1	S	source		_		
2	S	source	mb			
3	S	source				
4	G	gate	q;			
mb	D	mounting base; connected to drain	$\begin{array}{c} \begin{array}{c} \begin{array}{c} \end{array} \\ \begin{array}{c} \end{array} \\ 1 \end{array} \\ \begin{array}{c} 2 \end{array} \\ \begin{array}{c} 3 \end{array} \\ \begin{array}{c} 4 \end{array} \end{array}$	mbb076 S		
			SOT669 (LFPAK)			

3. Ordering information

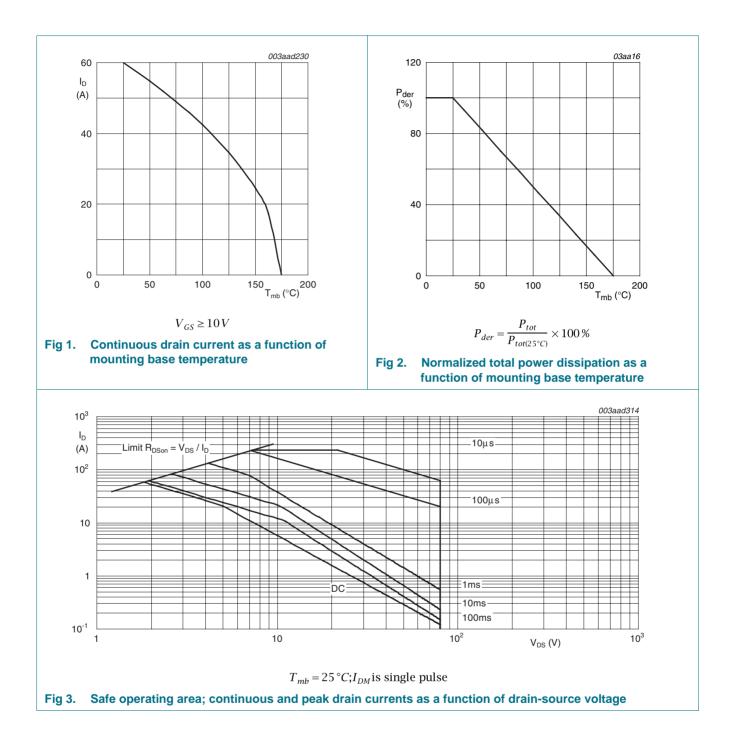
Table 3. Ordering information						
Type number	Package					
	Name	Description	Version			
PSMN013-80YS	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669			

4. Limiting values

Table 4.Limiting values

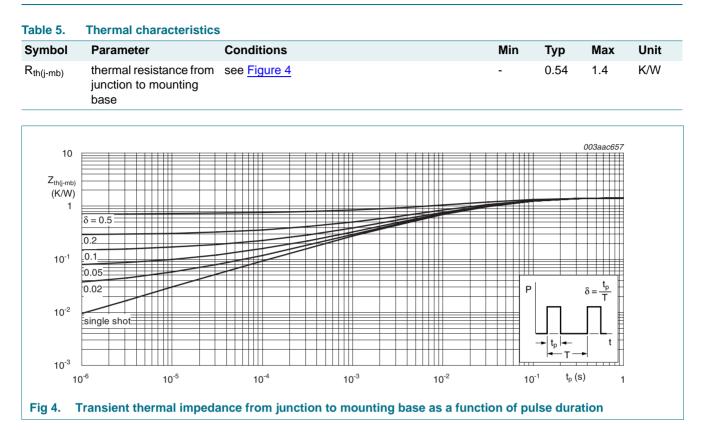
In accordance with the Absolute Maximum Rating System (IEC 60134).

Sumbol	Deremeter	Conditions	Mire	Mox	l lm it
Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	80	V
V _{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	80	V
V _{GS}	gate-source voltage		-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{100 \text{ Figure 1}}$	-	42	А
		V_{GS} = 10 V; T_{mb} = 25 °C; see <u>Figure 1</u>	-	60	А
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	233	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	106	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
T _{sld(M)}	peak soldering temperature		-	260	°C
Source-dr	ain diode				
I _S	source current	T _{mb} = 25 °C	-	60	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	233	А
Avalanche	e ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_{D} = 55 A; V_{sup} ≤ 80 V; R_{GS} = 50 $\Omega;$ unclamped	-	70	mJ



N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

5. Thermal characteristics



N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

6. Characteristics

Table 6. Characteristics

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS} drain-source breakdown voltage		$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$	73	-	-	V
		$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ C$	80	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	1	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	-	-	4.6	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	2	3	4	V
I _{DSS}	drain leakage current	V _{DS} = 80 V; V _{GS} = 0 V; T _j = 25 °C	-	-	3	μA
		$V_{DS} = 80 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125 \text{ °C}$	-	-	40	μA
I _{GSS}	gate leakage current	V_{GS} = -20 V; V_{DS} = 0 V; T_j = 25 °C	-	-	100	nA
		$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 15 A; T _j = 175 °C; see <u>Figure 12</u>	-	-	31	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 100 °C; see Figure 12	-	-	19.8	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 25 °C; see Figure 13	-	9.7	12.9	mΩ
R _G	internal gate resistance (AC)	f = 1 MHz	-	0.68	-	Ω
Dynamic o	characteristics					
Q _{G(tot)} total ga	total gate charge	$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}$	-	31	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}; \text{ see}$ Figure 14; see Figure 15	-	37	-	nC
Q _{GS}	gate-source charge	I_D = 25 A; V_{DS} = 40 V; V_{GS} = 10 V; see	-	11	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	Figure 14; see Figure 15	-	7	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	4	-	nC
Q _{GD}	gate-drain charge		-	8	-	nC
V _{GS(pl)}	gate-source plateau voltage	$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}$	-	4.8	-	V
C _{iss}	input capacitance	$V_{DS} = 40 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz};$	-	2420	-	рF
C _{oss}	output capacitance	T _j = 25 °C; see Figure 16	-	224	-	pF
C _{rss}	reverse transfer capacitance		-	125	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 40 \text{ V}; \text{ R}_{L} = 1.6 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	20	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	15	-	ns
t _{d(off)}	turn-off delay time		-	37	-	ns
t _f	fall time		-	10	-	ns

Symbol

Source-drain diode

PSMN013-80YS

Мах

Unit

N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

Min

Тур

V _{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j$ Figure 17	= 25 °C; see	-	0.84	1.2	V
t _{rr}	reverse recovery time	$I_{\rm S} = 50 \text{ A}; \text{ d}I_{\rm S}/\text{d}t = 100 \text{ A}$	√μs; V _{GS} = 0 V;	-	52	-	ns
Qr	recovered charge	$V_{DS} = 40 V$		-	91	-	nC
(A	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	003aad181	4000 C (pF) 3000			003aad187	
	30		2000			C _{rss}	
	10	4.5	1000				
	0 0.5 1	$V_{GS}(V) = 4$ 1.5 $V_{DS}(V)$ 2	0 <mark>0 0</mark>	3 6	9	12 V _{GS} (V)	
Fig 5.	Output characteristics: of function of drain-source		45 R _{DSon}	nd reverse trai			
Į	50		(mΩ) 35				
4	40						
;	20 T _j = 150 °C		25				
:	30 T _j = 150 °C	T _j = 25 °C		5 10	15		
:	$ \begin{array}{c} 30 \\ \hline T_{j} = 150 \circ C \\ \hline 10 \\ \hline 0 \end{array} $	$T_{j} = 25 \text{ °C}$ $4 \text{ V}_{GS} (V) \text{ 6}$	15	5 10 $T_i = 25 ^{\circ}C;I$			

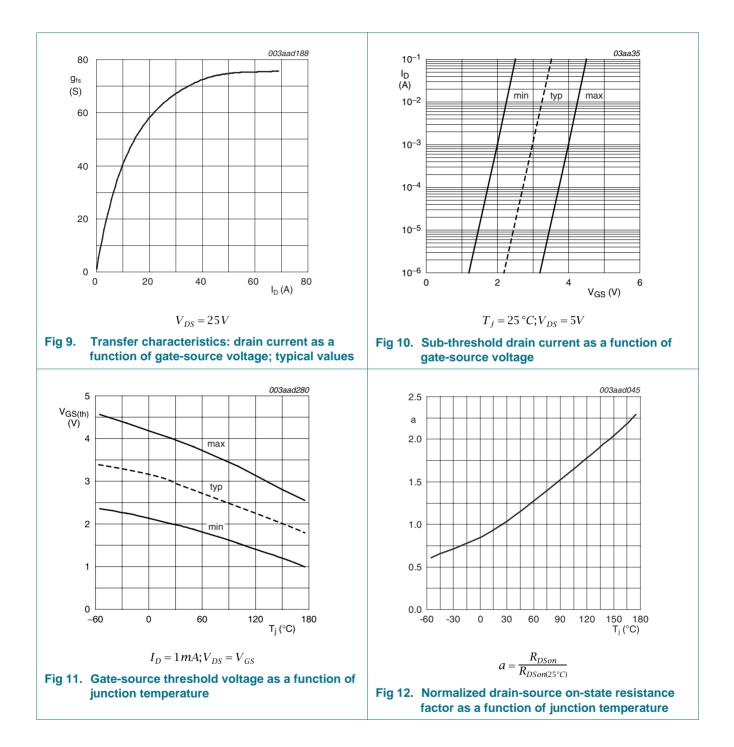
Table 6. Characteristics ...continued

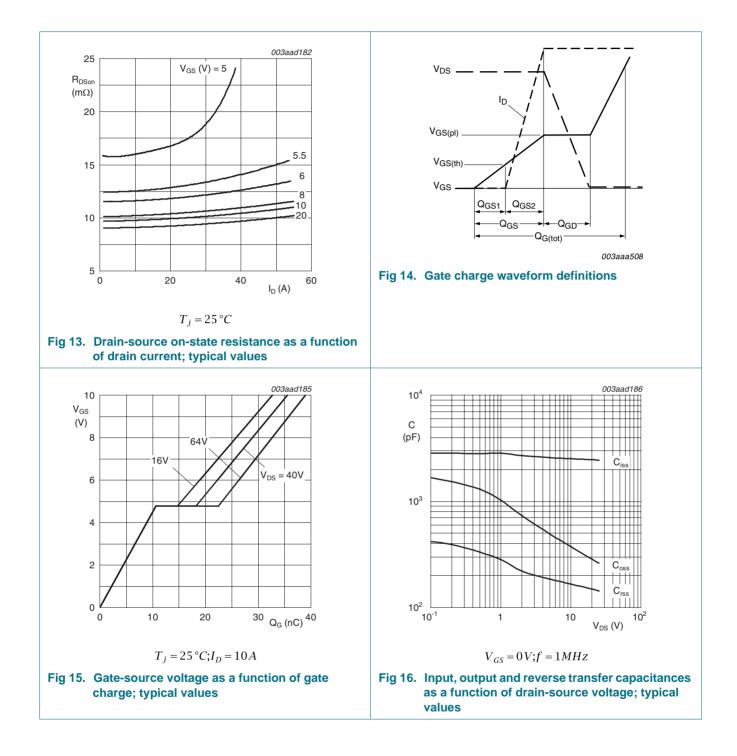
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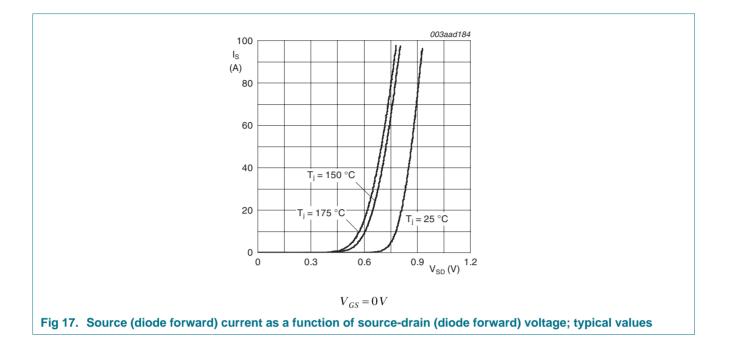
Tested to JEDEC standards where applicable.

Conditions

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N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

7. Package outline

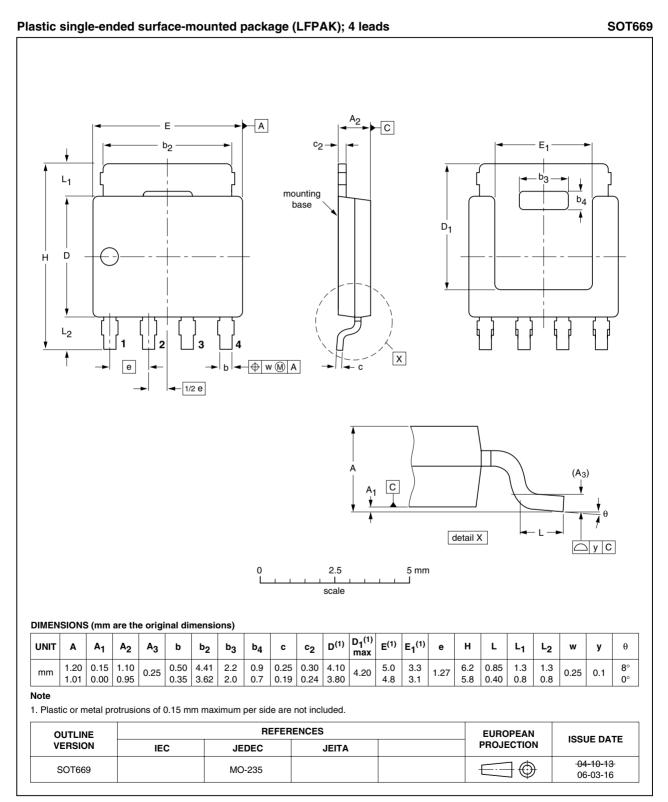


Fig 18. Package outline SOT669 (LFPAK)

PSMN013-80YS_1

N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

8. Revision history

Table 7. Revision his	able 7. Revision history			
Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN013-80YS_1	20090625	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions"

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PSMN013-80YS_1

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